## **COE 464, Term 042**

## **Testing of Digital Circuits**

## HW#3

Due date: Sunday, April 17

- **Q.1.** Consider the circuit shown in Figure 5.26(a) for a full-adder. Furthermore, consider the fault **N s-a-0** in the circuit.
  - (i) Generate a test for the fault using the **D algorithm**. Show all the details of the algorithm including the D-Frontier, the J-Frontier and the Decision tree. Whenever there are choices, select the choices in ascending alphabetical order. Verify your result by fault simulating the derived test using either PROOFS or HOPE.
  - (ii) Generate a test for the fault using the **PODEM algorithm**. Show all the details of the algorithm including the D-Frontier and the Decision tree. Whenever there are choices, select the choices in ascending alphabetical order. Verify your result by fault simulating the derived test using either PROOFS or HOPE.
  - (iii) Generate a test for this fault using HITEC and compare the obtained test to your solution.